

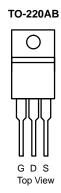
# N-Channel 130 V (D-S) 175 °C MOSFET

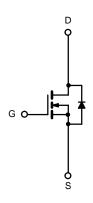
PRODUCT SUMMARY				
V <sub>DS</sub> (V)	(V) $R_{DS(on)}(\Omega)$			
130	0.0048 at V <sub>GS</sub> = 10 V	128 <sup>a</sup>		

### **FEATURES**

- DT-Trench Power MOSFET
- · New Package with Low Thermal Resistance
- 100 % R<sub>g</sub> Tested







N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS T <sub>C</sub> = 25 °C, unless otherwise noted						
Parameter	Symbol	Limit	Unit			
Drain-Source Voltage	V <sub>DS</sub>	130	V			
Gate-Source Voltage	V <sub>GS</sub>	± 20	7 v			
Continuous Drain Current (T, = 175 °C)	T <sub>C</sub> = 25 °C	,	128 <sup>a</sup>			
Continuous Diam Current (1 j = 175 C)	T <sub>C</sub> = 125 °C	I <sub>D</sub>	92 <sup>a</sup>	A		
Pulsed Drain Current	I <sub>DM</sub>	460				
Avalanche Current		I <sub>AR</sub>	85			
Repetitive Avalanche Energy <sup>b</sup>	L = 0.1 mH	E <sub>AR</sub>	280	mJ		
Maximum Power Dissipation <sup>b</sup>	T <sub>C</sub> = 25 °C	Б	375 <sup>c</sup>	W		
waximum rower bissipation	T <sub>A</sub> = 25 °C	P <sub>D</sub>	3.95	] vv		
Operating Junction and Storage Temperature	Range	T <sub>J</sub> , T <sub>stg</sub>	- 55 to 175	°C		

THERMAL RESISTANCE RATINGS							
Parameter		Symbol	Limit	Unit			
Junction-to-Ambient	PCB Mount (TO-220) <sup>d</sup>	R <sub>thJA</sub>	40	°C/W			
Junction-to-Case (Drain)		R <sub>thJC</sub>	0.4	C/VV			

#### Notes:

- a. Package limited.
- b. Duty cycle ≤ 1 %.
- c. See SOA curve for voltage derating.
  d. When mounted on 1" square PCB (FR-4 material).



Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static	•						
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{DS} = 0 \text{ V}, I_{D} = 250  \mu\text{A}$	130			V	
Gate-Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_D = 250 \mu A$	2		4	V	
Gate-Body Leakage	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
		V <sub>DS</sub> = 100 V, V <sub>GS</sub> = 0 V			1		
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = 100 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 125 °C			50	μA	
		V <sub>DS</sub> = 100 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 175 °C			250		
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	120			Α	
		V <sub>GS</sub> = 10 V, I <sub>D</sub> = 60 A		0.0048	0.0055		
Drain-Source On-State Resistance <sup>a</sup>	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 30 A, T <sub>J</sub> = 125 °C			0.0089	Ω	
		V <sub>GS</sub> = 10 V, I <sub>D</sub> = 30 A, T <sub>J</sub> = 175 °C			0.0135		
Forward Transconductance <sup>a</sup>	9 <sub>fs</sub>	V <sub>DS</sub> = 15 V, I <sub>D</sub> = 30 A	25			S	
Dynamic <sup>b</sup>							
Input Capacitance	C <sub>iss</sub>			6200		pF	
Output Capacitance	C <sub>oss</sub>	$V_{GS} = 0 \text{ V}, V_{DS} = 25 \text{ V}, f = 1 \text{ MHz}$		930			
Reverse Transfer Capacitance	C <sub>rss</sub>			420			
Total Gate Charge <sup>c</sup>	Qg			130	160	nC	
Gate-Source Charge <sup>c</sup>	Q <sub>gs</sub>	$V_{DS} = 50 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 85 \text{ A}$		24			
Gate-Drain Charge <sup>c</sup>	Q <sub>gd</sub>			24			
Gate Resistance	R <sub>g</sub>		1.0		6.2	Ω	
Turn-On Delay Time <sup>c</sup>	t <sub>d(on)</sub>			20	30		
Rise Time <sup>c</sup>	t <sub>r</sub>	$V_{DD} = 50 \text{ V}, R_{L} = 0.6 \Omega$		125	200		
Turn-Off Delay Time <sup>c</sup>	t <sub>d(off)</sub>	$I_D \cong 85 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 2.5 \Omega$		55	85	ns	
Fall Time <sup>c</sup>	t <sub>f</sub>			130	195		
Source-Drain Diode Ratings and Ch	aracteristics -	Γ <sub>C</sub> = 25 °C <sup>b</sup>					
Continuous Current	I <sub>S</sub>				118	^	
Pulsed Current	I <sub>SM</sub>				440	Α	
Forward Voltage <sup>a</sup>	V <sub>SD</sub>	I <sub>F</sub> = 85 A, V <sub>GS</sub> = 0 V		1.0	1.5	V	
Reverse Recovery Time	t <sub>rr</sub>			70	140	ns	
Peak Reverse Recovery Charge	I <sub>RM(REC)</sub>	I <sub>F</sub> = 50 A, dI/dt = 100 A/μs		5.5	10	Α	
Reverse Recovery Charge				0.19	0.35	μC	

#### Notes:

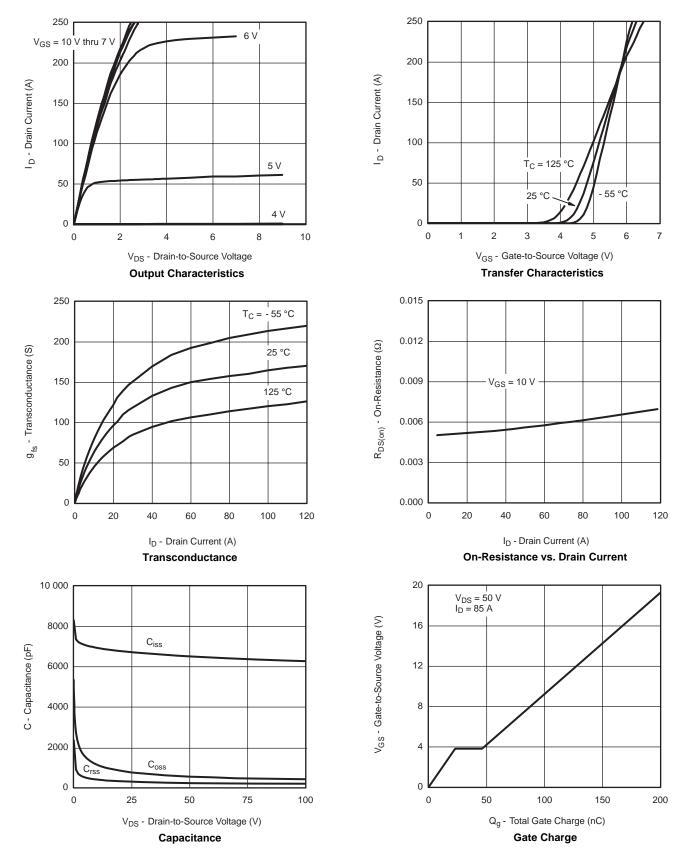
- a. Pulse test; pulse width  $\leq$  300 µs, duty cycle  $\leq$  2 %.
- b. Guaranteed by design, not subject to production testing.
- c. Independent of operating temperature.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.





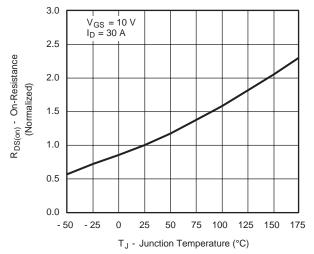
## TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



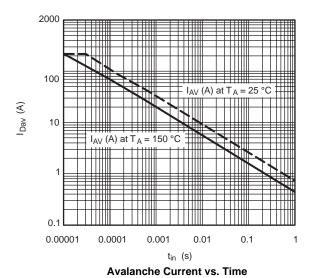


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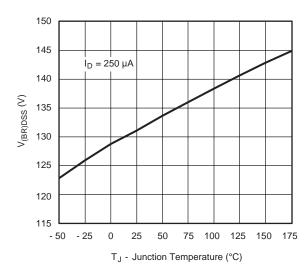
#### TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



#### On-Resistance vs. Junction Temperature



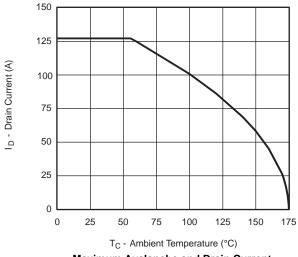
Source-Drain Diode Forward Voltage



Drain Source Breakdown vs. Junction Temperature

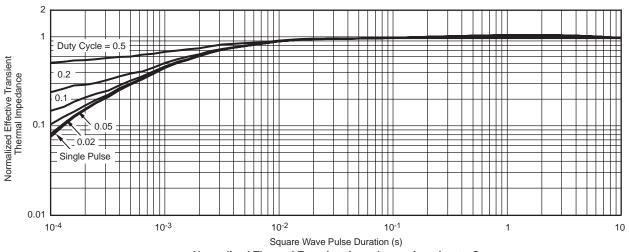


#### **THERMAL RATINGS**



1000 100 10 µs I<sub>D</sub> - Drain Current (A) Limited 100 µs by R<sub>DS(on)\*</sub> ШШ 10 1 ms 10 ms 100 ms, DC T<sub>C</sub> = 25 °C Single Pulse 0.1 0.1 1000 10 V<sub>DS</sub> - Drain-to-Source Voltage (V) \*  $V_{GS}$  > minimum  $V_{GS}$  at which  $R_{DS(on)}$  is specified Safe Operating Area

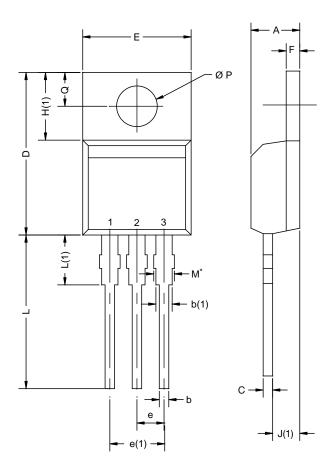
**Maximum Avalanche and Drain Current** vs. Case Temperature



Normalized Thermal Transient Impedance, Junction-to-Case



## **TO-220AB**



	MILLIN	IETERS	INC	HES	
DIM.	MIN.	MAX.	MIN.	MAX.	
Α	4.25	4.65	0.167	0.183	
b	0.69	1.01	0.027	0.040	
b(1)	1.20	1.73	0.047	0.068	
С	0.36	0.61	0.014	0.024	
D	14.85	15.49	0.585	0.610	
Е	10.04	10.51	0.395	0.414	
е	2.41	2.67	0.095	0.105	
e(1)	4.88	5.28	0.192	0.208	
F	1.14	1.40	0.045	0.055	
H(1)	6.09	6.48	0.240	0.255	
J(1)	2.41	2.92	0.095	0.115	
L	13.35	14.02	0.526	0.552	
L(1)	3.32	3.82	0.131	0.150	
ØΡ	3.54	3.94	0.139	0.155	
Q	2.60	3.00	0.102	0.118	
ECN: X12-0208-Rev. N, 08-Oct-12 DWG: 5471					

#### Notes

 $<sup>^{*}</sup>$  M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM





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